

Asynchronous fault detection in IEEE P1687 instrument network

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

BASTION : board and SoC test instrumentation for ageing and no failure found

Jutman, Artur; Lotz, Christophe; Larsson, Erik; Sonza Reorda, Matteo; Jenihhin, Maksim; Raik, Jaan Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 115-120 : ill
<https://doi.org/10.23919/DATE.2017.7926968>

Health management for self-aware SoCs based on IEEE 1687 infrastructure

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill
<https://doi.org/10.1109/MDAT.2017.2750902>

IEEE 1687 compliant ecosystem for embedded instrumentation access and in-field health monitoring

Tšertov, Anton; Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 9 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532559>

IEEE P1687 IJTAG demonstrator on FPGA

Shibin, Konstantin; Aleksejev, Igor; Jutman, Artur; Devadze, Sergei DATE 2012 University Booth : Design Automation and Test in Europe : Dresden, Germany, March 12-16, 2012 2012 / 1 p. : ill

Invited paper: System-Wide Fault Management based on IEEE P1687 IJTAG

Jutman, Artur; Devadze, Sergei; Aleksejev, Jevgeni 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpellier, France 2011 / [4] p.: ill <https://ieeexplore.ieee.org/document/5981520>

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Squillero, Giovanni; Gürsoy, Cemil Cem; Jenihhin, Maksim VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill <https://doi.org/10.1109/LATW.2016.7483342>

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

A suite of IEEE 1687 benchmark networks

Tšertov, Anton; Jutman, Artur; Devadze, Sergei 2016 IEEE International Test Conference (ITC) : proceedings 2016 / art. 6.1, p. 1-10 : ill <https://doi.org/10.1109/TEST.2016.7805840>

System-wide fault management based on IEEE P1687 IJTAG

Shibin, Konstantin; Jutman, Artur; Devadze, Sergei Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5. oktoobril 2012, Laulasmaa 2012 / p. 81-84 : ill